Memory FRAM

CMOS

256 K (32 K × 8) Bit

MB85R256H

■ DESCRIPTIONS

The MB85R256H is an FRAM (Ferroelectric Random Access Memory) chip in a configuration of 32,768 words x 8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells.

Unlike SRAM, MB85R256H is able to retain data without back-up battery.

The memory cells used for the MB85R256H has improved at least 10¹⁰ times of read/write access per bit, significantly outperforming FLASH memory and E²PROM in durability.

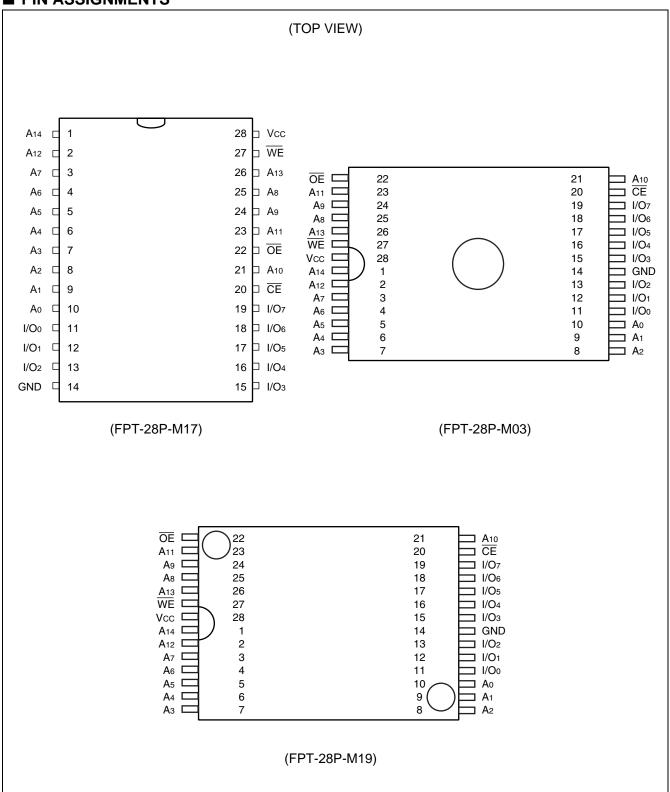
The MB85R256H uses a pseudo - SRAM interface compatible with conventional asynchronous SRAM.

■ FEATURES

- Bit configuration: 32,768 words x 8 bits
- Read/write durability: 10¹⁰ times/bit (Min)
- Peripheral circuit CMOS construction
- Operating power supply voltage: 2.7 V to 3.6 V
- Operating temperature range: -40 °C to +85 °C
- 28-pin, SOP flat package
- 28-pin, TSOP(1) flat package



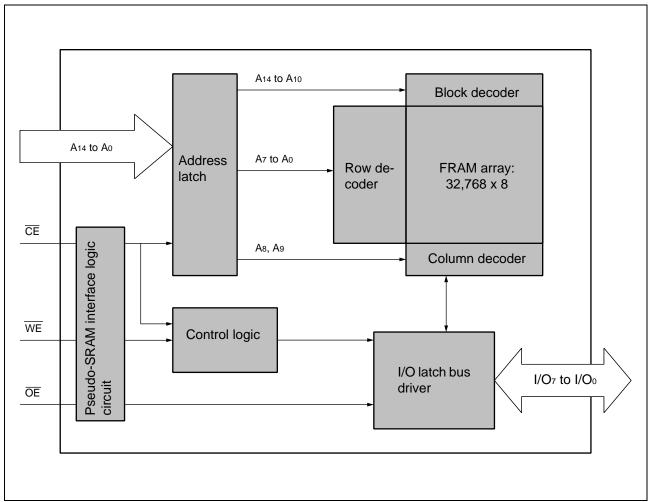
■ PIN ASSIGNMENTS



■ PIN DESCRIPTIONS

Pin No.	Pin name	Function
10 to 1	Ao to A ₁₄	Address Input
11 to 13, 15 to 19	I/O ₀ to I/O ₇	Data input/output
20	CE	Chip enable input
27	WE	Write Enable input
22	ŌĒ	Output enable input
28	Vcc	Power supply (+ 3.3 V Typ)
14	GND	Ground

■ BLOCK DIAGRAM



■ FUNCTION LIST

Operation mode	CE	WE	ŌĒ	I/O ₇ to I/O ₀	Power supply current
Standby precharge	Н	×	×	High-Z	Standby
Stariuby precharge	×	L	L	riigii-Z	(I _{SB})
Latch address	L	Ł	Ł	_	_
Write	L	L	Н	Data input	
Read	L	Н	L	Data output	Operation (Icc)
Output Disable	×	Н	Н	High-Z	

H: High level, L: Low level, x: Irrespective of "H" or "L"

■ ABSOLUTE MAXIMUM RANGES

Parameter	Symbol	Rat	Unit	
	Symbol	Min	Max	Onit
Power supply voltage	Vcc	- 0.5	+ 4.0	V
Input voltage	VIN	- 0.5	Vcc + 0.5	V
Output voltage	Vouт	- 0.5	Vcc + 0.5	V
Operating temperature	TA	- 40	+ 85	°C
Storage temperature	Tstg	- 40	+ 125	°C

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

■ RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit		
raiailletei	Symbol	Min	Тур	Max	Offic
Power supply voltage	Vcc	2.7	3.3	3.6	V
High level input voltage	Vıн	0.8 × Vcc	_	Vcc + 0.5	V
Low level input voltage	VıL	- 0.5	_	+ 0.6	V
Operating temperature	TA	- 40	_	+ 85	°C

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

■ ELECTRICAL CHARACTERISTICS

1. DC Characteristics

(within recommended operating conditions)

Parameter	Symbol	Conditions		Unit		
Farameter	Symbol	Conditions	Min	Тур	Max	Offic
Input leakage current		V _{IN} = 0 V to V _{CC}	_	_	10	μΑ
Output leakage current	I LO	$V_{OUT} = 0 \text{ V to } V_{CC},$ $\overline{CE} = V_{IH} \text{ or } \overline{OE} = V_{IH}$	_	_	10	μΑ
Operating power supply current	Icc	$\overline{\text{CE}} = 0.2 \text{ V},$ Other Inputs = $V_{\text{CC}} - 0.2 \text{ V}/0.2 \text{ V},$ t_{RC} (Min), Ii/o = 0 mA	_	5	10	mA
Standby current	IsB	\overline{CE} , \overline{WE} , $\overline{OE} \ge V_{CC}$	_	5	100	μΑ
High level output voltage	Vон	Іон = - 100 μΑ	0.8 × Vcc	_	_	V
Low level output voltage	Vol	IoL = 1.0 mA	_	_	0.4	V

2. AC Characteristics

(1) Read cycle

(within recommended operating conditions)

Parameter	Symbol	Va	Unit	
Farameter	Symbol	Min	Max	Offic
Read cycle time	trc	150	_	
CE active time	t ca	70	2,000	
Read pulse width	t RP	70	2,000	
Precharge time	t PC	80	_	
Address setup time	t AS	0		ne
Address hold time	t ah	25	_	ns
CE access time	t ce	_	70	
OE access time	toe	_	70	
CE output floating time	t HZ	_	25	
OE output floating time	tонz	_	25	

(2) Write cycle

(within recommended operating conditions)

Parameter	Symbol	Va	lue	Unit
Farameter	Symbol	Min	Max	Oilit
Write cycle time	t wc	150	_	
CE active time	t ca	70	2,000	
Write pulse width	t wp	70	2,000	
Precharge time	t PC	80	_	
Address setup time	t as	0	_	ne
Address hold time	t ah	25	_	ns
Data setup time	t DS	50	_	
Data hold time	t DH	0	_	
Write set up time	t ws	0	_	
Write hold time	twн	0	_	

(3) Power ON/OFF sequence

(within recommended operating conditions)

Parameter	Symbol		Unit		
Farameter	Symbol	Min	Тур	Max	Ollit
CE LEVEL hold time at power OFF	tpd	80	_	_	ns
CE LEVEL hold time at power ON	tpu	80	_	_	ns
Power interval	tpi	1	_	_	S

3. Pin Capacitance

Parameter	Symbol	Conditions		Value		Unit
Farameter	Symbol	Conditions	Min	Тур	Max	Oille
Input capacitance	Cin	$V_{IN} = V_{OUT} = GND,$	_	_	10	pF
output capacitance	Соит	$f = 1 \text{ MHz}, T_A = +25 ^{\circ}\text{C}$	_	_	10	pF

4. AC Characteristics Test Condition

Power supply voltage : 2.7 V to 3.6 V Input voltage amplitude : 0.3 V to 2.7 V

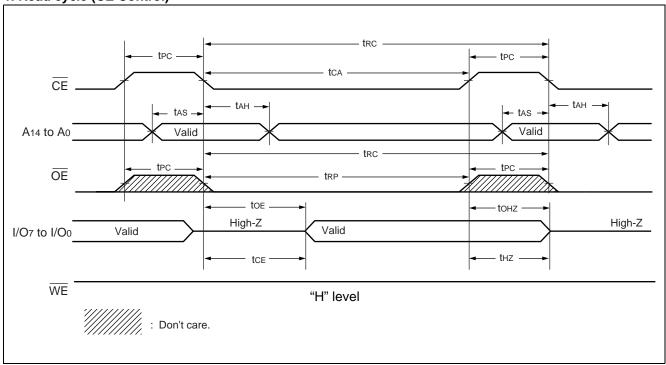
Input rising time : 10 ns
Input falling time : 10 ns
Input evaluation level : 2.0 V/0.8 V

Output evaluation level : 2.0 V/0.8 V Output load : 100 pF

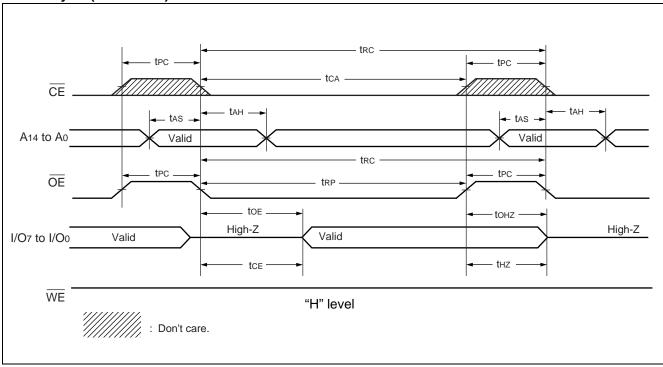
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■ TIMING DIAGRAM

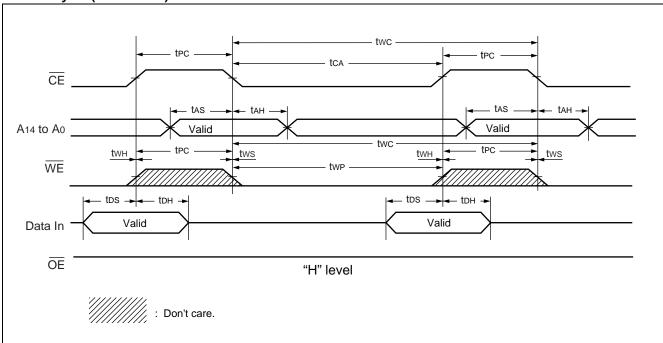
1. Read cycle (CE Control)



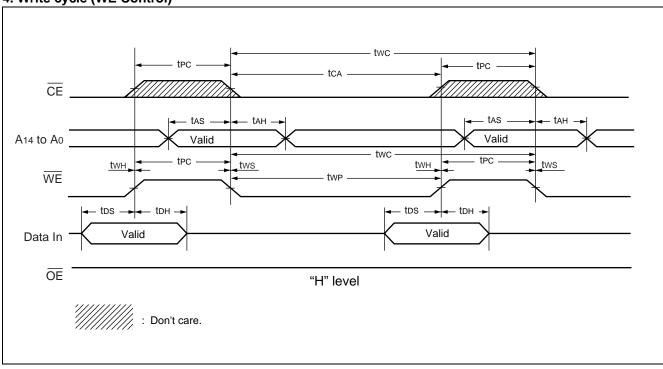
2. Read cycle (OE Control)



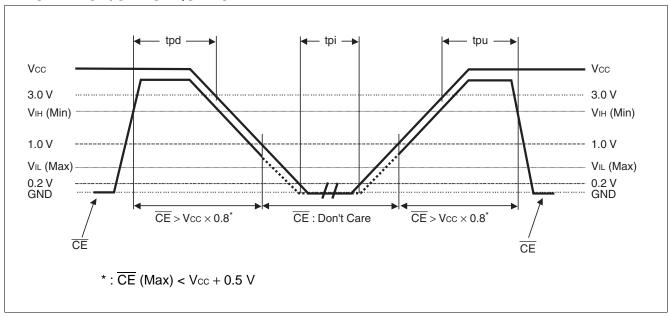
3. Write cycle (CE Control)



4. Write cycle (WE Control)



■ POWER ON/OFF SEQUENCE



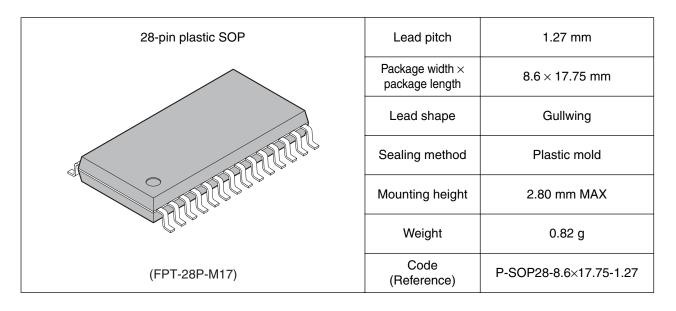
■ NOTES ON USE

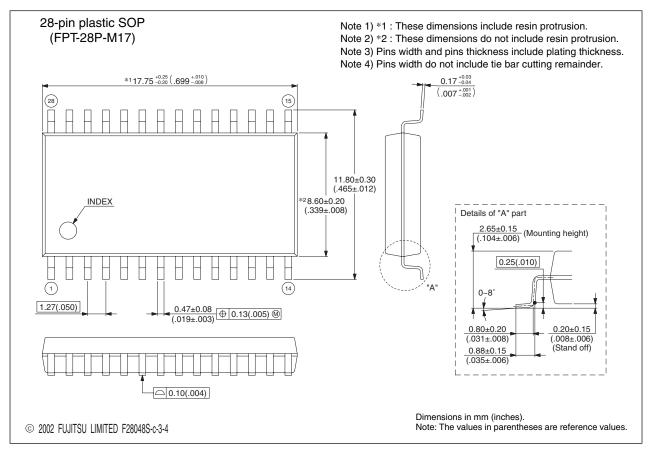
After IR reflow, the hold of data that was written before IR reflow is not guaranteed.

■ ORDERING INFORMATION

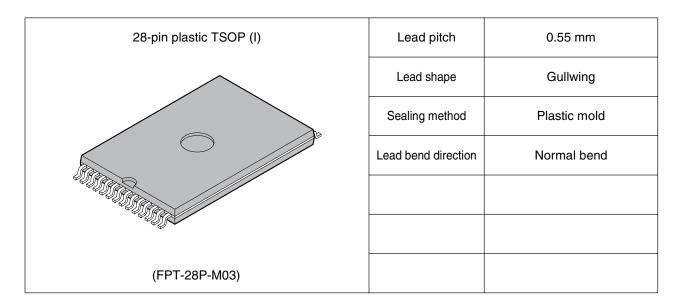
Part number	Package	Remarks
MB85R256HPF	28-pin, plastic SOP (FPT-28P-M17)	
MB85R256HPFTN	28-pin, plastic TSOP(1) (FPT-28P-M03)	
MB85R256HPFCN	28-pin, plastic TSOP(1) (FPT-28P-M19)	Cu Lead Frame

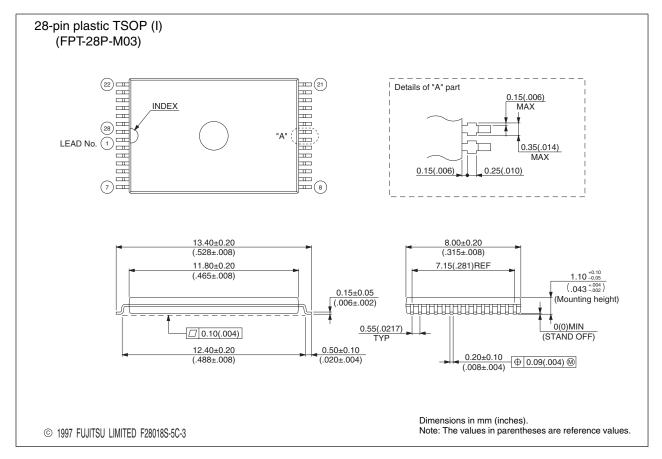
■ PACKAGE DIMENSIONS





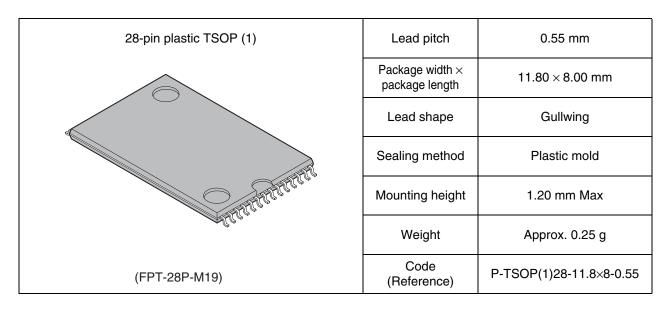
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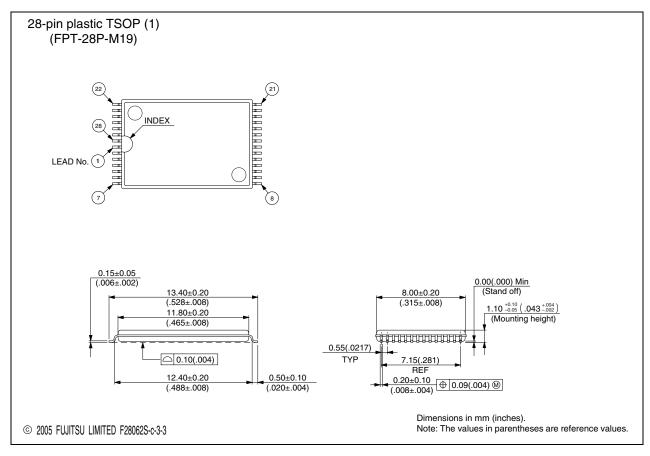




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